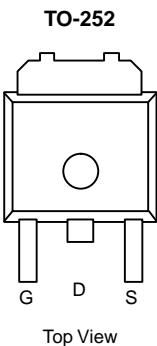


P-Channel 40 V (D-S) MOSFET

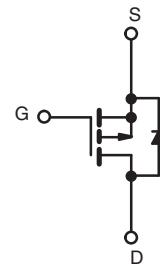
PRODUCT SUMMARY	
V_{DS} (V)	-40
$R_{DS(on)}$ (Ω) at $V_{GS} = -10$ V	0.012
$R_{DS(on)}$ (Ω) at $V_{GS} = -4.5$ V	0.015
I_D (A)	-50
Configuration	Single

FEATURES

- TrenchFET® power MOSFET
- Package with low thermal resistance
- 100 % R_g and UIS tested



Top View



P-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS ($T_C = 25$ °C, unless otherwise noted)

PARAMETER	SYMBOL	LIMIT	UNIT
Drain-Source Voltage	V_{DS}	-40	V
Gate-Source Voltage	V_{GS}	± 20	
Continuous Drain Current	I_D	-50	A
		-39	
Continuous Source Current (Diode Conduction) ^a	I_S	-50	
Pulsed Drain Current ^b	I_{DM}	-200	
Single Pulse Avalanche Current	I_{AS}	-40	mJ
Single Pulse Avalanche Energy	E_{AS}	80	
Maximum Power Dissipation ^b	P_D	3	
		136	
		45	
Operating Junction and Storage Temperature Range	T_J, T_{stg}	-55 to +175	°C

THERMAL RESISTANCE RATINGS

PARAMETER	SYMBOL	LIMIT	UNIT
Junction-to-Ambient	R_{thJA}	50	°C/W
Junction-to-Case (Drain)	R_{thJC}	1.1	

Notes

- Package limited.
- Pulse test; pulse width ≤ 300 μ s, duty cycle ≤ 2 %.
- When mounted on 1" square PCB (FR4 material).
- Parametric verification ongoing.

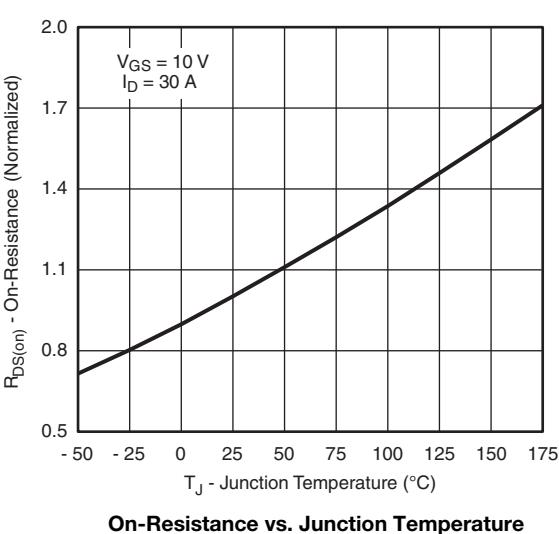
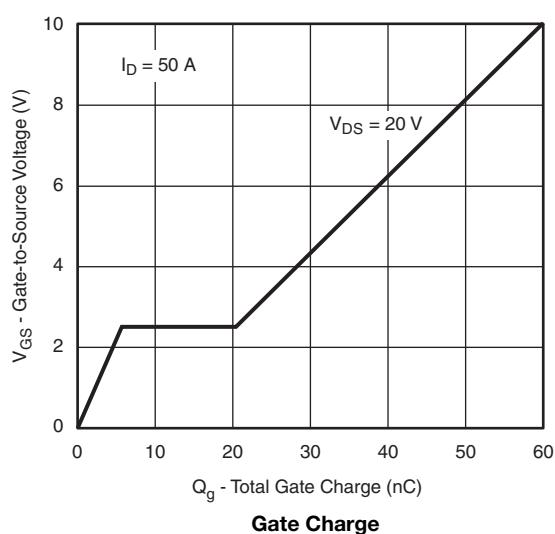
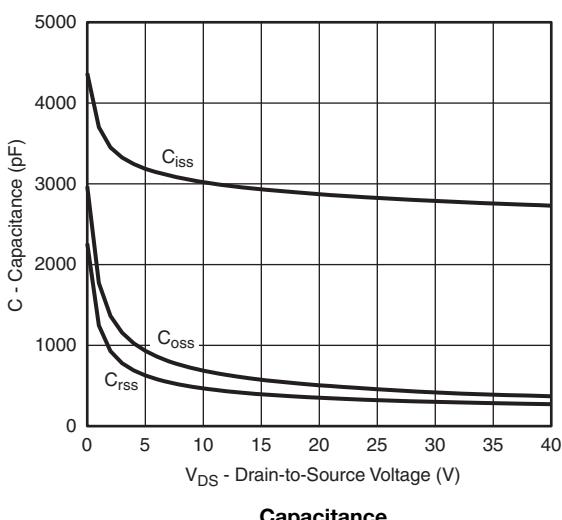
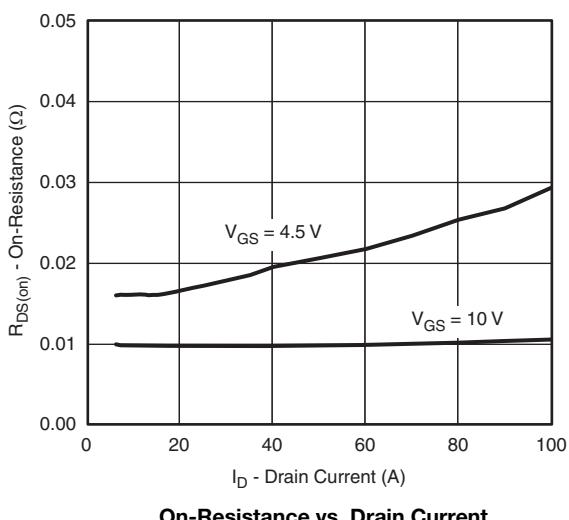
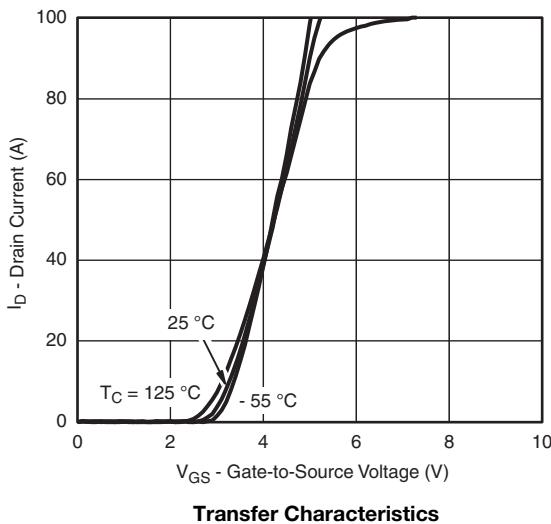
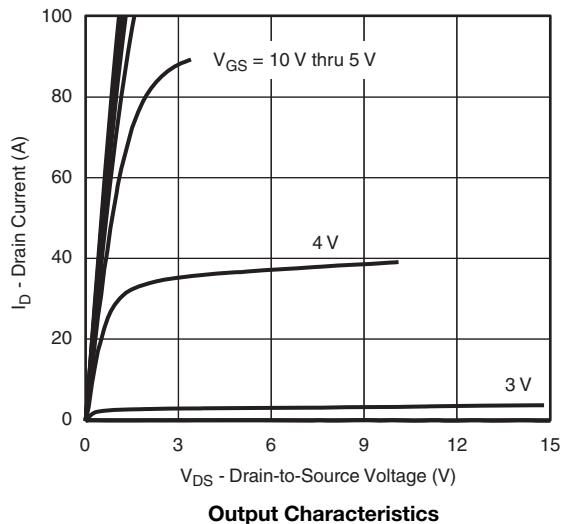
SPECIFICATIONS ($T_C = 25^\circ\text{C}$, unless otherwise noted)								
PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT	
Static								
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0 \text{ V}$, $I_D = -250 \mu\text{A}$		-40	-	-	V	
Gate-Source Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}$, $I_D = -250 \mu\text{A}$		-1.5	-	-2.5		
Gate-Source Leakage	I_{GSS}	$V_{DS} = 0 \text{ V}$, $V_{GS} = \pm 20 \text{ V}$		-	-	± 100	nA	
Zero Gate Voltage Drain Current	I_{DSS}	$V_{GS} = 0 \text{ V}$	$V_{DS} = -40 \text{ V}$	-	-	-1	μA	
		$V_{GS} = 0 \text{ V}$	$V_{DS} = -40 \text{ V}$, $T_J = 125^\circ\text{C}$	-	-	-50		
		$V_{GS} = 0 \text{ V}$	$V_{DS} = -40 \text{ V}$, $T_J = 175^\circ\text{C}$	-	-	-150		
On-State Drain Current ^a	$I_{D(\text{on})}$	$V_{GS} = -10 \text{ V}$	$V_{DS} \leq -5 \text{ V}$	-50	-	-	A	
Drain-Source On-State Resistance ^a	$R_{DS(\text{on})}$	$V_{GS} = -10 \text{ V}$	$I_D = -17 \text{ A}$	-	0.012	0.014	Ω	
		$V_{GS} = -10 \text{ V}$	$I_D = -50 \text{ A}$, $T_J = 125^\circ\text{C}$	-	-	0.017		
		$V_{GS} = -10 \text{ V}$	$I_D = -50 \text{ A}$, $T_J = 175^\circ\text{C}$	-	-	0.020		
		$V_{GS} = -4.5 \text{ V}$	$I_D = -14 \text{ A}$	-	0.015	0.018		
Forward Transconductance ^a	g_{fs}	$V_{DS} = -15 \text{ V}$, $I_D = -17 \text{ A}$		-	61	-	S	
Dynamic b								
Input Capacitance	C_{iss}	$V_{GS} = 0 \text{ V}$	$V_{DS} = -25 \text{ V}$, $f = 1 \text{ MHz}$	-	2872	3950	pF	
Output Capacitance	C_{oss}			-	508	635		
Reverse Transfer Capacitance	C_{rss}			-	352	440		
Total Gate Charge ^c	Q_g	$V_{GS} = -10 \text{ V}$	$V_{DS} = -30 \text{ V}$, $I_D = -50 \text{ A}$	-	60	80	nC	
Gate-Source Charge ^c	Q_{gs}			-	5.7	8.6		
Gate-Drain Charge ^c	Q_{gd}			-	14.7	22		
Gate Resistance	R_g	$f = 1 \text{ MHz}$		1.5	3	4.5	Ω	
Turn-On Delay Time ^c	$t_{d(\text{on})}$	$V_{DD} = -20 \text{ V}$, $R_L = 0.4 \Omega$ $I_D \geq -50 \text{ A}$, $V_{GEN} = -10 \text{ V}$, $R_g = 1 \Omega$				-	ns	
Rise Time ^c	t_r					10		
Turn-Off Delay Time ^c	$t_{d(\text{off})}$					12		
Fall Time ^c	t_f					40		
Source-Drain Diode Ratings and Characteristics b								
Pulsed Current ^a	I_{SM}			-	-	-200	A	
Forward Voltage	V_{SD}	$I_F = -50 \text{ A}$, $V_{GS} = 0 \text{ V}$		-	-1	-1.5	V	

Notes

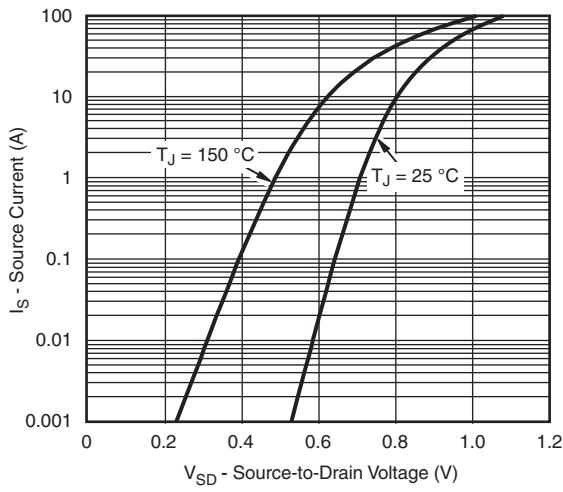
- a. Pulse test; pulse width $\leq 300 \mu\text{s}$, duty cycle $\leq 2\%$.
- b. Guaranteed by design, not subject to production testing.
- c. Independent of operating temperature.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

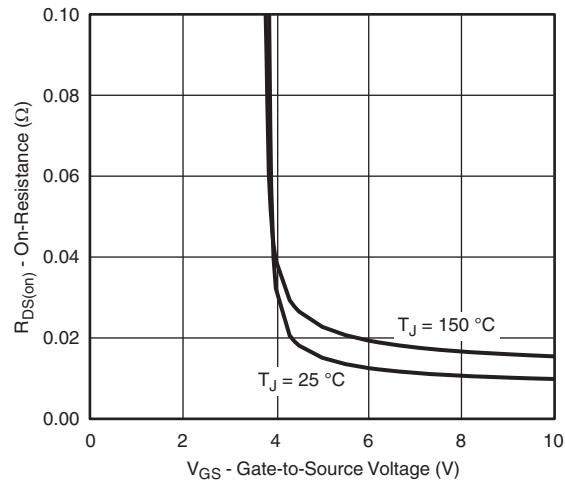
TYPICAL CHARACTERISTICS ($T_A = 25^\circ\text{C}$, unless otherwise noted)



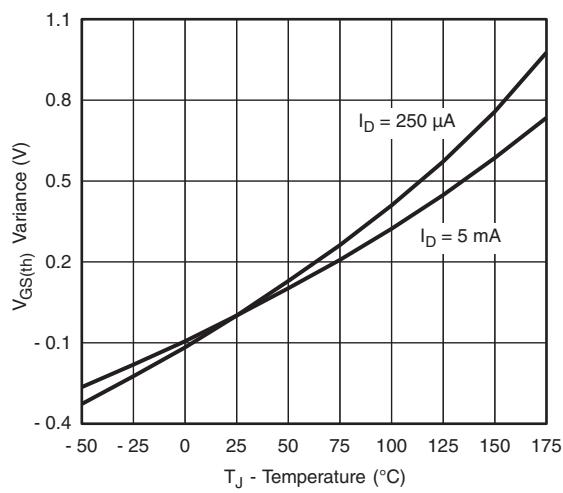
TYPICAL CHARACTERISTICS ($T_A = 25^\circ\text{C}$, unless otherwise noted)



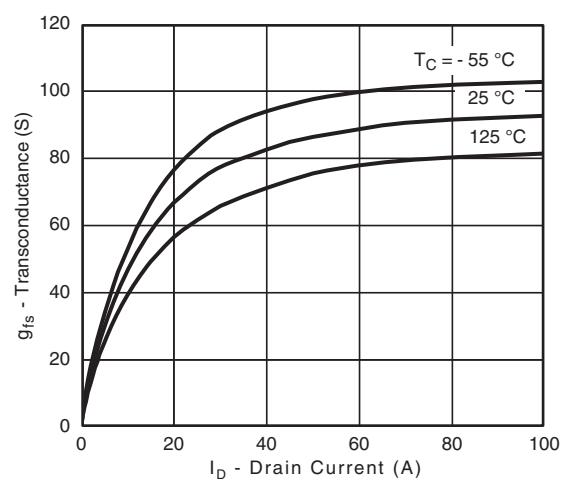
Source Drain Diode Forward Voltage



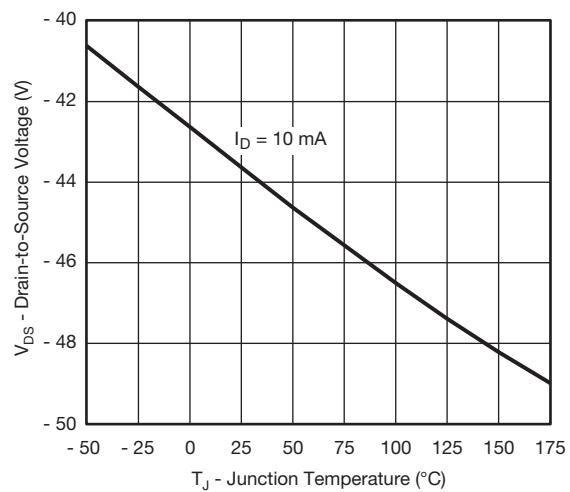
On-Resistance vs. Gate-to Source Voltage



Threshold Voltage

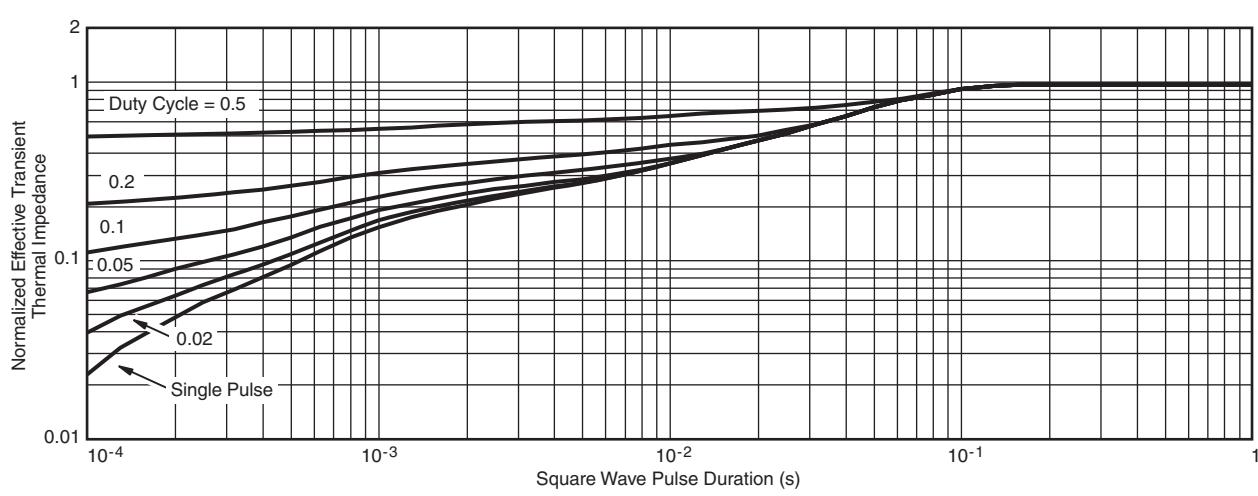
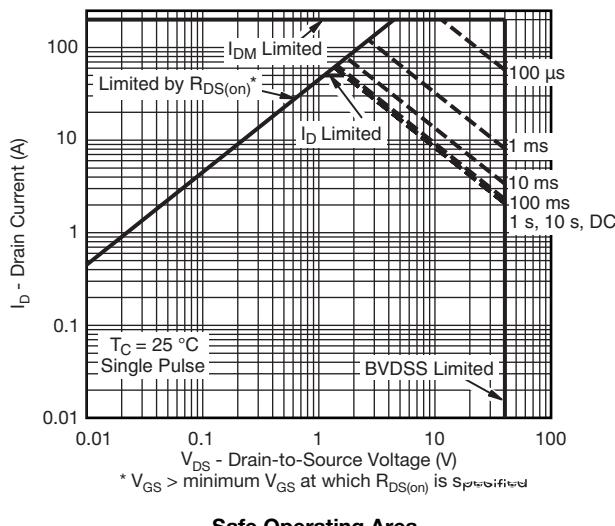


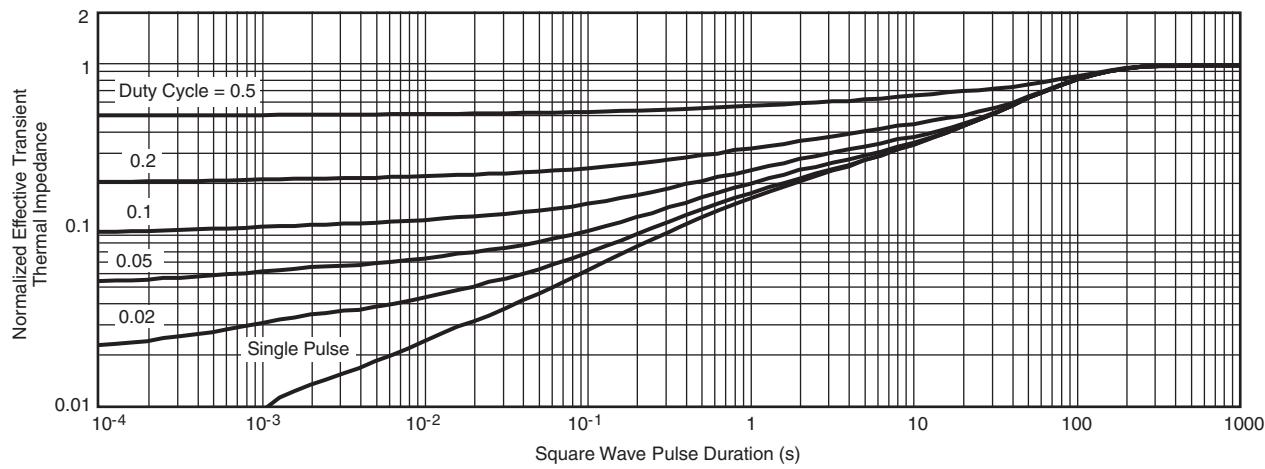
Transconductance



Drain Source Breakdown vs. Junction Temperature

TYPICAL CHARACTERISTICS ($T_A = 25^\circ\text{C}$, unless otherwise noted)





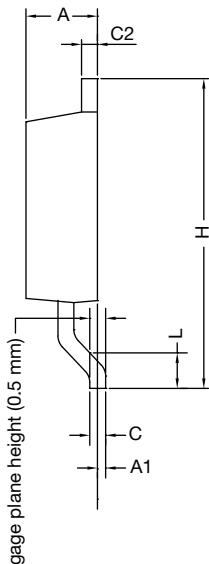
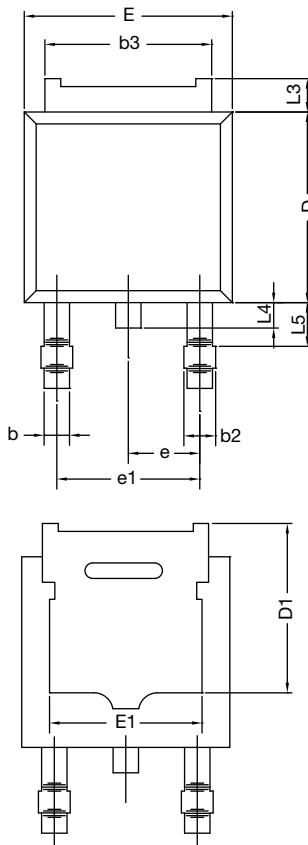
Normalized Thermal Transient Impedance, Junction-to-Ambient

Note

- The characteristics shown in the two graphs
 - Normalized Transient Thermal Impedance Junction-to-Ambient (25 °C)
 - Normalized Transient Thermal Impedance Junction-to-Case (25 °C)

are given for general guidelines only to enable the user to get a "ball park" indication of part capabilities. The data are extracted from single pulse transient thermal impedance characteristics which are developed from empirical measurements. The latter is valid for the part mounted on printed circuit board - FR4, size 1" x 1" x 0.062", double sided with 2 oz. copper, 100 % on both sides. The part capabilities can widely vary depending on actual application parameters and operating conditions.

TO-252AA Case Outline



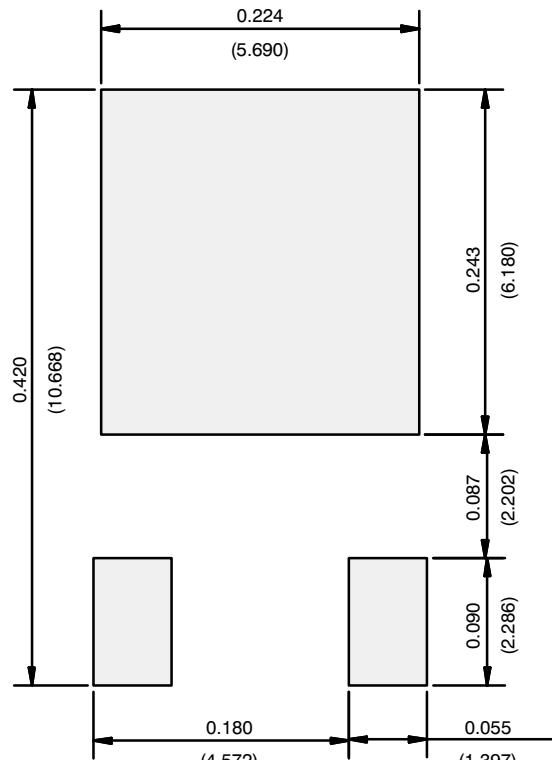
DIM.	MILLIMETERS		INCHES	
	MIN.	MAX.	MIN.	MAX.
A	2.18	2.38	0.086	0.094
A1	-	0.127	-	0.005
b	0.64	0.88	0.025	0.035
b2	0.76	1.14	0.030	0.045
b3	4.95	5.46	0.195	0.215
C	0.46	0.61	0.018	0.024
C2	0.46	0.89	0.018	0.035
D	5.97	6.22	0.235	0.245
D1	4.10	-	0.161	-
E	6.35	6.73	0.250	0.265
E1	4.32	-	0.170	-
H	9.40	10.41	0.370	0.410
e	2.28 BSC		0.090 BSC	
e1	4.56 BSC		0.180 BSC	
L	1.40	1.78	0.055	0.070
L3	0.89	1.27	0.035	0.050
L4	-	1.02	-	0.040
L5	1.01	1.52	0.040	0.060

ECN: T13-0592-Rev. A, 02-Sep-13
DWG: 6019

Note

- Dimension L3 is for reference only.

RECOMMENDED MINIMUM PADS FOR DPAK (TO-252)



Recommended Minimum Pads
Dimensions in Inches/(mm)